Notice of References Cited Application/Control No. 10/720,342 Examiner Thuy V. Tran Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0214478 A1	11-2003	Yoo et al.	345/102
	В	US-2003/0142060 A1	07-2003	Lee et al.	345/102
	C	US-6,674,250	01-2004	Cho et al.	315/291
	D	US-6,661,181	12-2003	Shin, Chung-Hyuk	315/169.4
	Е	US-6,469,453	10-2002	Tajika et al.	315/199
	F	US-5,971,567	10-1999	Van Duijneveldt, Wido	362/296
	G	US-5,619,402	04-1997	Liu, Kwang H.	363/20
	Н	US-			
	_	US-			
	J	US-			
	κ	US-			
	L	US-		·	
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	R					
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	Т					

NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.